

MMD65R380Q 650V 0.38Ω N-channel MOSFET

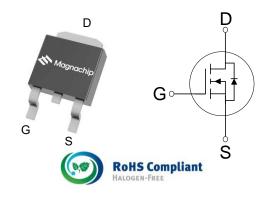
Description

MMD65R380Q is power MOSFET using Magnachip's advanced super junction technology that can realize very low on-resistance and gate charge. It will provide much high efficiency by using optimized charge coupling technology. These user friendly devices give an advantage of low EMI to designers as well as low switching loss.

Key Parameters

Parameter	Value	Unit
V _{DS} @ T _{j, max}	700	V
R _{DS(on),max}	0.38	Ω
V _{GS(th), typ}	3	V
Ι _D	10.6	А
Q _{g, typ}	20.6	nC





Features

- Low power loss by high speed switching and low on-resistance
- 100% avalanche tested
- Green package Pb-free plating, Halogen-free

Applications

- PFC power supply stages
- Switching applications
- Adapter

Ordering Information

Order Code	Marking	Temp. Range	Package	Packing	RoHS Status
MMD65R380QRH	65R380Q	-55 ~ 150°C	TO-252	Reel	compliant



Parameter	Symbol	Rating	Unit	Note
Drain – source voltage	V _{DSS}	650	V	
Gate – source voltage	V _{GSS}	±30	V	
		10.6	А	T _C = 25°C
Continuous drain current	١ _D	6.7	А	T _C = 100°C
Pulsed drain current ⁽¹⁾	I _{DM}	31.8	А	
Power dissipation	PD	83.3	W	
Single - pulse avalanche energy	E _{AS}	215	mJ	
MOSFET dv/dt ruggedness	dv/dt	50	V/ns	
Diode dv/dt ruggedness ⁽²⁾	dv/dt	15	V/ns	
Storage temperature	T _{stg}	-55 ~150	°C	
Maximum operating junction temperature	Tj	150	°C	

■ Absolute Maximum Rating (T_c=25°C unless otherwise specified)

1) Pulse width tP limited by Tj,max.

2) $I_{SD} \leq I_D, V_{DS peak} \leq V_{(BR)DSS.}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case max	R _{thjc}	1.5	°C/W
Thermal resistance, junction-ambient max ⁽³⁾	R _{thja}	62	°C/W

3) Device mounted on minimal footprint of PCB.



Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Drain – source breakdown voltage	V _{(BR)DSS}	650	-	-	V	V_{GS} = 0V, I _D = 250uA
Gate threshold voltage	$V_{\text{GS(th)}}$	2	3	4	V	$V_{\text{DS}} = V_{\text{GS}, \text{ I}_{\text{D}}} = 250 \text{uA}$
Zero gate voltage drain current	I _{DSS}	-	-	1	uA	V_{DS} = 650V, V_{GS} = 0V
Gate leakage current	I _{GSS}	-	-	100	nA	V_{GS} = ±30V, V_{DS} = 0V
Drain-source on state resistance	R _{DS(ON)}	-	0.34	0.38	Ω	V _{GS} = 10V, I _D = 3.2A

■ Static Characteristics (T_c=25°C unless otherwise specified)

■ Dynamic Characteristics (T_c=25°C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Input capacitance	C _{iss}	-	763	-		
Output capacitance	Coss	-	896	-	۳Ľ	V _{DS} = 25V, V _{GS} = 0V, f = 1.0MHz
Reverse transfer capacitance	C _{rss}	-	38.7	-	pF	
Effective output capacitance energy related ⁽⁴⁾	C _{o(er)}	-	23.7	-		$V_{DS} = 0V$ to 520V, $V_{GS} = 0V$, f = 1.0MHz
Turn on delay time	$\mathbf{t}_{d(on)}$	-	19	-	ns	V _{GS} = 10V, R _G = 25Ω, V _{DS} = 325V, I _D = 10.6A
Rise time	tr	-	38	-		
Turn off delay time	$t_{d(off)}$	-	108	-		
Fall time	t _f	-	36	-		
Total gate charge	Q_{g}	-	20.6	-		
Gate – source charge	Q_gs	-	7.5	-	nC	V_{GS} = 10V, V_{DS} = 520V, I_{D} = 10.6A
Gate – drain charge	Q_{gd}	-	5.3	-		
Gate resistance	R_{G}	-	19	-	Ω	V _{GS} = 0V, f = 1.0MHz

4) $C_{o(er)}$ is a capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0V to 80% $V_{(BR)DSS}$

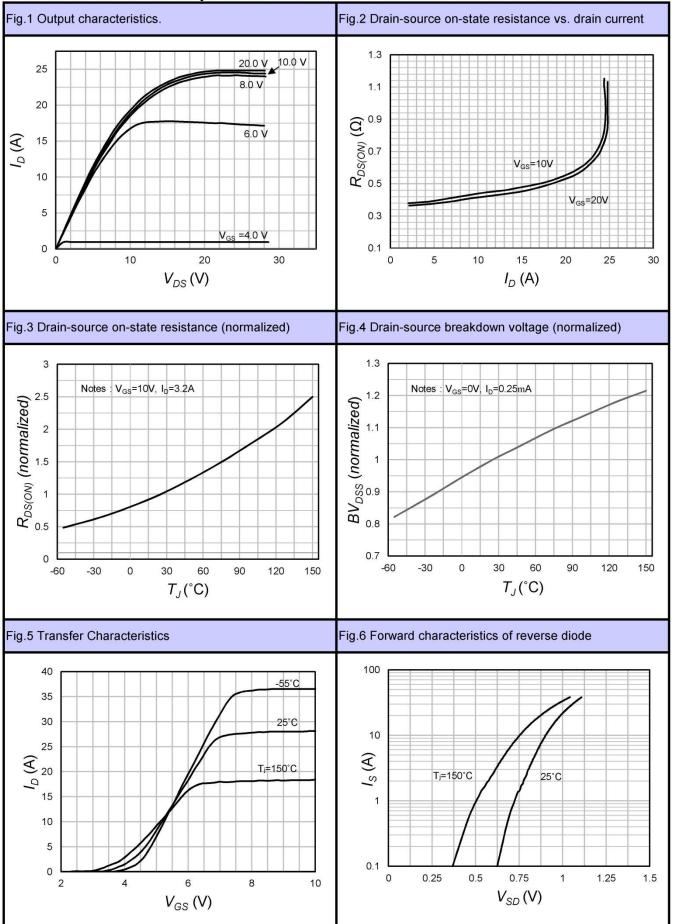


Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Continuous diode forward current	I _S	-	-	10.6	А	
Diode forward voltage	V_{SD}	-	-	1.4	V	$I_{\rm S} = 10.6 A, V_{\rm GS} = 0 V$
Reverse recovery time	t _{rr}	-	324	-	ns	10.00
Reverse recovery charge	Qrr	-	3.8	-	uC	Is = 10.6A di/dt = 100A/us
Reverse recovery current	I _{rrm}	-	23.2	-	А	V _{DD} = 100V

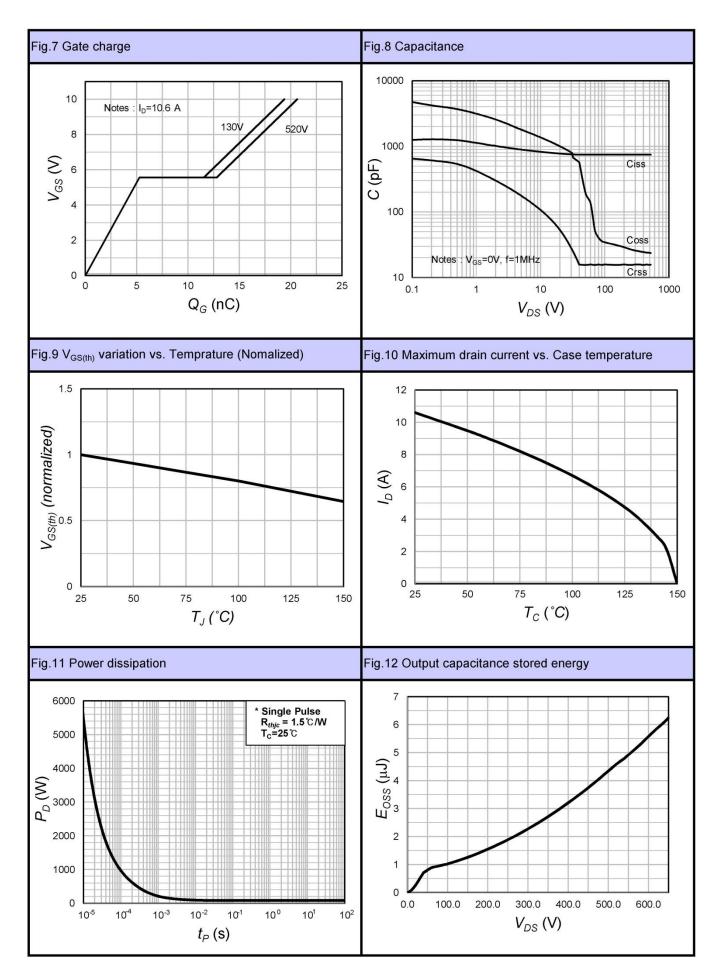
■ Reverse Diode Characteristics (T_c=25°C unless otherwise specified)



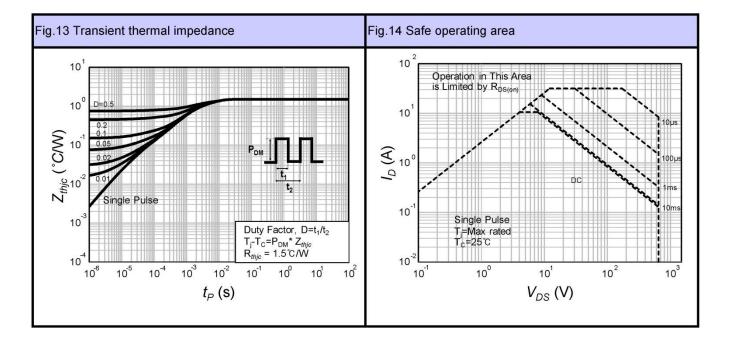
Characteristic Graph













Test Circuit

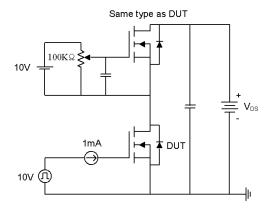


Fig15-1. Gate charge measurement circuit

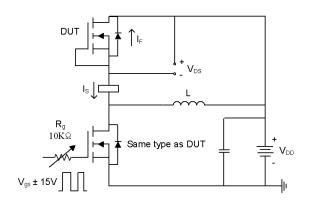


Fig16-1. Diode reverse recovery test circuit

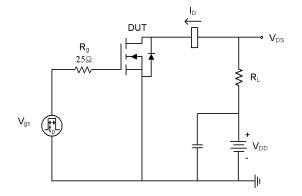


Fig17-1. Switching time test circuit for resistive load

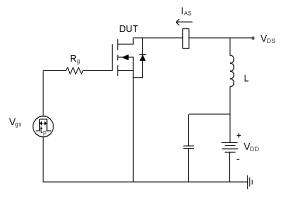


Fig18-1. Unclamped inductive load test circuit

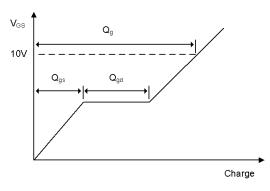


Fig15-2. Gate charge waveform

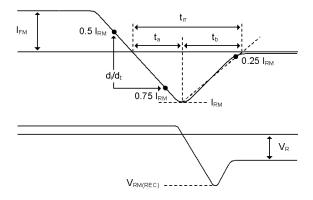


Fig16-2. Diode reverse recovery test waveform

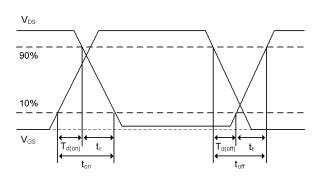


Fig17-2. Switching time waveform

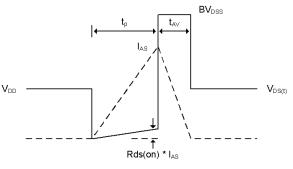
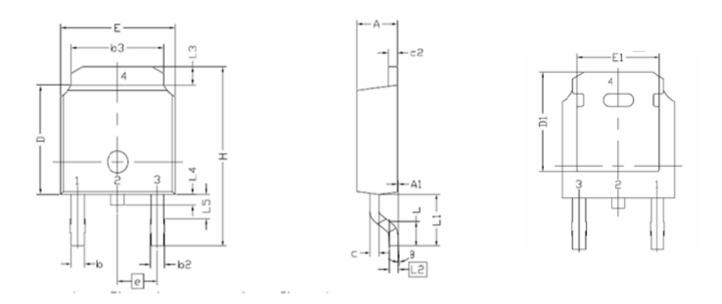


Fig18-2. Unclamped inductive waveform



Physical Dimension

TO-252(2L)



			[0]
Symbol	Min.	Nom.	Max.
E	6,35	-	6,73
L	1,40	1,52	1,78
L1		2,74 REF	
L2		0,508 BCS	
L3	0,89	-	1,27
L4	-	-	1,02
L5 D	1,14	-	1,52
D	5,97	6,10	6,22
Н	9,40	-	10,41
b	0,64	-	0,89
b2	0,76	-	1,14
b3	4,95	-	5,46
е		2,286 BSC	_
A	2,18	-	2,39
A1	-	-	0,13
с	0,46	-	0,61
c2	0,46	-	0,89
D1 E1	5,21	-	-
E1	4,32	-	-
Θ	0,00	-	10,00

Note : Package body size, length and width do not include mold flash, protrusions and gate burrs.



DISCLAIMER:

The Products are not designed for use in hostile environments, including, without limitation, aircraft, nuclear power generation, medical appliances, and devices or systems in which malfunction of any Product can reasonably be expected to result in a personal injury. Seller's customers using or selling Seller's products for use in such applications do so at their own risk and agree to fully defend and indemnify Seller.

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